Search Notes			

Application/Contro	ol No.	Applicant(s)/Patent und Reexamination	ler
09/770,541		BANERJEE ET AL.	
Examiner		Art Unit	
Chris C. Chu		2815	

	SEARCHED			
Class	Subclass	Date	Examiner	
717	140 & 141	4/11/2005	C.C.	
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INTERFERENCE SEARCHED		
Subclass	Date	Examiner
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	Subclass	Subclass Date

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	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	4/11/2005	C.C.